Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/767,765	OGAWA, HIDEHIKO	
Examiner	Art Unit	
Thomas D. Lee	2625	

	SEAR	CHED	
Class	Subclass	Date	Examiner
358	1.15, 402, 440	12/8/2005	TDL
379	100.01	12/8/2005	TDL
379	100.08	12/8/2005	TDL
379	100.13	12/8/2005	TDL
379	100.17	12/8/2005	TDL
updated		5/23/2006	TDL

INT	NTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			-
Interference Search Printout		5/23/2006	TDL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		